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SERIAL NUMBER 10/084,338	FILING DATE 02/28/2002 RULE	CLASS 714	GROUP ART UNIT 2133	ATTORNEY DOCKET NO. 50090-478
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APPLICANTS

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Yoshihiro Nagura, Tokyo, JAPAN;

**** CONTINUING DATA *******

None filed 6/24/04
YSPM

**** FOREIGN APPLICATIONS *******

JAPAN 2001-224899 07/25/2001

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

** 03/25/2002

Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY JAPAN	SHEETS DRAWING 9	TOTAL CLAIMS 8	INDEPENDENT CLAIMS 3
35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged	Examiner's Signature <i>[Signature]</i> Initials				

ADDRESS

McDermott, Will & Emery
600 13th Street, N.W.
Washington ,DC 20005-3096

TITLE

Testing device of semiconductor integrated circuit and test method therefor

FILING FEE RECEIVED 1020	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees
		<input type="checkbox"/> 1.16 Fees (Filing)
		<input type="checkbox"/> 1.17 Fees (Processing Ext. of time)
		<input type="checkbox"/> 1.18 Fees (Issue)
		<input type="checkbox"/> Other
		<input type="checkbox"/> Credit